# **USB97CFDC**



# **USB Floppy Disk Controller**

#### **FEATURES**

- 3.3 Volt, Low Power Operation
- Complete USB Specification 1.1 Compatibility
  - Includes USB Transceiver
  - Based on an Enhanced Version of SMSC's Industry Proven USB97C100 USB Controller
- Complete System Solution Including USB Mass Storage Class Compliant Win98/2000 Driver and Firmware
  - Supports 640K, 720K, 1.44M, 1.2M Windows 98
     J, and 1.2M NEC DOS 6.x Formats
  - Supports Both the UFI and SFF8070i Command Sets
  - Supports USB Mass Storage Compliant Bootable Floppy BIOS
  - 4ms Seek Times
  - USB 1.1 Compliance, Including Low Power Device Class SUSPEND Mode Operation and Power Control of Disk Drive
  - Disk Drive Feedback of Readiness Upon Power Re-Application Option
  - Option for Ultra High Performance Using Additional Caching SRAM
  - Support for Floppy Drive Power Control
- Contains SMSC's Industry Proven Floppy Disk Controller
  - Licensed CMOS 765B Floppy Disk Controller
  - Supports Single Normal or Three Mode Floppy Drives

- Supports Vertical Recording Format and High Capacity Drives in User Written Firmware Applications
- Detects All Overrun and Underrun Conditions
- Sophisticated Power Control Circuitry (PCC) Including Multiple Powerdown Modes for Reduced Power Consumption
- Enhanced Digital Data Separator
  - 1 Mbps, 500 Kbps, 300 Kbps, 250 Kbps Data
  - Programmable Precompensation Modes
- Intelligent Auto Power Management
  - <300µA SUSPEND Current
  - <75mA Operating Current
- External Program Memory Interface
  - 32K Byte Code Space (Supplied Firmware Requires 16KB Memory)
  - Flash, SRAM, or EPROM Memory
- 4KB Internal Buffer SRAM for High Performance Operation
- Optional External Cache Memory
  - Up to 16K x 8 External SRAM may be Used for Custom Tape/ Drive Applications
- Integrated 14.318 MHz Crystal Driver Circuit
- 100 pin TQFP package (12.0 x 12.0 mm footprint)
  - 25% smaller body size than other 100 pin TQFP packages

### **ORDERING INFORMATION**

Order Number: USB97CFDC-MN 100 Pin TQFP Package @ STANDARD MICROSYSTEMS CORPORATION (SMSC) 2000



80 Arkay Drive Hauppauge, NY 11788 (631) 435-6000 FAX (631) 273-3123

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#### **GENERAL DESCRIPTION**

The USB97CFDC is an integration of the USB97C102 Enhanced Multi-Endpoint USB Peripheral Controller, without its integrated hub functions, and the SMSC Floppy Disk Controller used in many of its Super IO products, such as the FDC37C869. Special care in the interconnection of the two devices has been taken to assure the lowest possible system current draw (<300µA) during SUSPEND mode operation.

Provisions for external Flash Memory up to 32K bytes for program storage is provided.

Although not required for standard floppy operation, provisions for 16K bytes of external buffer SRAM, in addition to that included in the USB97C102 core, is also provided for extended applications, such as tape drives and for other special applications.

Several pins are provided for controlling external power control elements and sensing specialized drive functions.

Note: SMSC has developed and supplies firmware and drivers for this device to implement a standard three mode or dual mode Floppy Disk Drive system with drive power control. If the customer desires to develop his own firmware and/or drivers for this system, he may contact SMSC to obtain a complete engineering specification which details all the internal block functions and register maps of the USB97CFDC to allow custom programs to be written for this device.

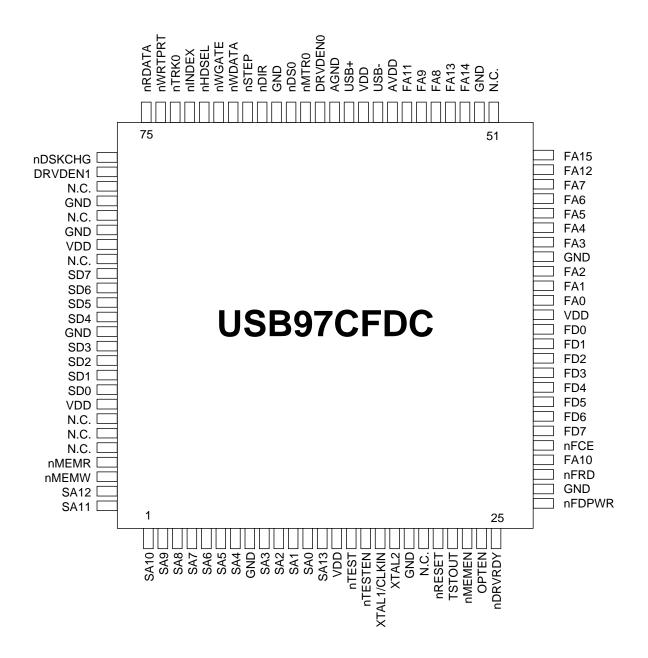
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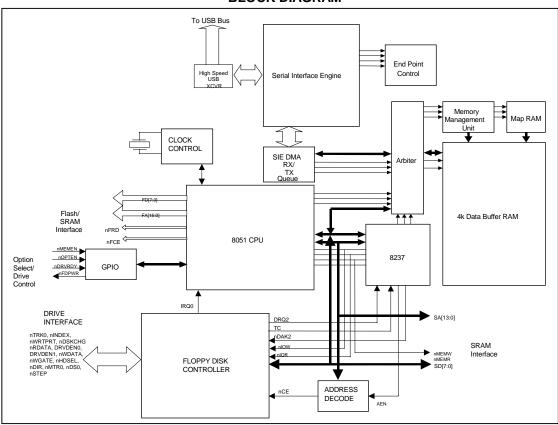
# **DESCRIPTION OF PIN FUNCTIONS**

	FLOPPY DISK INTE	ERFACE (14 Pins)	
nTRK0	nINDEX	nWRTPRT	nDSKCHG
nRDATA	DRVDEN0	DRVDEN1	nSTEP
nWDATA	nWGATE	nHDSEL	nDIR
nDSO	nMTR0		
	USB INTERFA	ACE (4 Pins)	
USB+	USB-	AVDD	AGND
	FLASH ROM INTE	RFACE (26 Pins)	
FD0	FD1	FD2	FD3
FD4	FD5	FD6	FD7
FA0	FA1	FA2	FA3
FA4	FA5	FA6	FA7
FA8	FA9	FA10	FA11
FA12	FA13	FA14	FA15
nFRD	nFCE		
	SRAM/IO INTERI	FACE (24 Pins)	
SD0	SD1	SD2	SD3
SD4	SD5	SD6	SD7
SA0	SA1	SA2	SA3
SA4	SA5	SA6	SA7
SA8	SA9	SA10	SA11
SA12	SA13	nMEMR	nMEMW
	MISC (10	Pins)	
nMEMEN	OPTEN	nDRVRDY	nFDPWR
XTAL1/CLKIN	XTAL2	nRESET	nTEST
TST_OUT	nTESTEN		
P	OWER, GROUNDS, and I	NO CONNECTS (22 Pins)	

#### **PIN CONFIGURATION**



# **BLOCK DIAGRAM**



# **Pin Descriptions**

			BUFFER	
PIN NO.	NAME	SYMBOL	TYPE	DESCRIPTION
		FLO	PPY DISK I	NTERFACE
75	Read Disk Data	nRDATA	IS	Raw serial bit stream from the disk drive, low active. Each falling edge represents a flux transition of the encoded data.
69	Write Data	nWDATA	OD12	This active low high current driver provides the encoded data to the disk drive. Each falling edge causes a flux transition on the media.
71	Head Select	nHDSEL	OD12	This high current output selects the floppy disk side for reading or writing. A logic "1" on this pin means side 0 will be accessed, while a logic "0" means side 1 will be accessed.
67	Direction Control	nDIR	OD12	This high current low active output determines the direction of the head movement. A logic "1" on this pin means outward motion, while a logic "0" means inward motion.
68	Step Pulse	nSTEP	OD12	This active low high current driver issues a low pulse for each track-to-track movement of the head.
76	Disk Change	nDSKCHG	IS	This input senses that the drive door is open or that the diskette has possibly been changed since the last drive selection.

			BUFFER	
PIN NO.	NAME	SYMBOL	TYPE	DESCRIPTION
63	DRVDEN 0	DRVDEN 0	OD12	An active low on this pin indicates a disk drive spindle speed change from 300 RPM to 360 RPM or 1.2M format disks in three mode drives. This pin should be tied to the disk drives spindle speed control input pin.
77	DRVDEN 1	DRVDEN1	OD12	Reserved for future use.
70	Write Gate	nWGATE	OD12	This active low high current driver allows current to flow through the write head. It becomes active just prior to writing to the diskette.
73	Track 0	nTRK0	IS	This active low Schmitt Trigger input senses from the disk drive that the head is positioned over the outermost track.
72	Index	nINDEX	IS	This active low Schmitt Trigger input senses from the disk drive that the head is positioned over the beginning of a track, as marked by an index hole.
74	Write Protect		IS	This active low Schmitt Trigger input senses from the disk drive that a disk is write protected. Any write command is ignored.
64	Motor On 0	nMTR0	OD12	This active low open drain output selects motor drive 0.
65	Drive Select 0	nDS0	OD12	This active low open drain output selects drive 0.
		Ī	USB INTER	
59 61	USB Bus Data	USB- USB+	IO-U	These pins connect to the USB data signals through 33 ohm series resistors. The USB+ line should be pulled up with a 5%, 1.5K ohm resistor to indicate that this is a high speed USB device.
58	USB Transceiver Supply	AVDD		This is the 3.3V supply to the internal USB transceiver.
62	USB Transceiver Ground	AGND		This is the supply ground for the internal USB transceiver.
		F	LASH INTE	ERFACE
31-38	Flash Memory Data Bus	FD[7:0]	IO8	These signals are used to transfer data between the internal 8051 and the external FLASH program memory.
50, 53, 54, 49, 57, 29, 56, 55, 48- 44, 42-40,	Flash Memory Address Bus	FA[15:0]	O8	These signals address memory locations within the FLASH memory.
28	Flash Memory Read Strobe	nFRD	O8	Flash ROM Read; active low
30	Flash Memory Chip Select		O8	Flash ROM Chip Select; active low
	T		RAM/IO INT	
1-7, 9-13, 99,100	SRAM Memory Bus	SA[13:0]	O8	These signals provide the memory address to an external SRAM buffer.
84-87, 89-92	SRAM Memory Data Bus	SD[7:0]	I/O8	These signals are used to transfer data to/from the SRAM Memory.
97	SRAM Memory Read Strobe		O8	Memory read; active low This active low signal indicates that data is to be driven onto the data bus by the SRAM. Data will be latched internal to the chip on the rising edge of this signal
98	SRAM Memory Write Strobe	nMEMW	O8	Memory write; active low This active low signal indicates to the SRAM to load data from the data bus on its rising edge.

DIN NO	NAME	CVMDOL	BUFFER TYPE	DESCRIPTION
PIN NO.	NAME	SYMBOL	MISCELLA	DESCRIPTION
17	Crystal	XTAL1/	ICLKx	14.318Mhz Crystal or clock input.
17	_	CLKIN	ICLIX	This pin can be connected to one terminal of the crystal or can be connected to an external 14.318Mhz clock when a crystal is not used.
18	Crystal Output	XTAL2	OCLKx	14.318Mhz Crystal  This is the other terminal of the crystal, or left open when an external clock source is used to drive XTAL1/CLKIN. It may not be used to drive any external circuitry other than the crystal circuit.
23	SRAM Enable	nMEMEN	O24	An active low signal is output on this pin to enable the optional external SRAM for extended FDC write and read caching for ultra high performance applications.
24	Option Enable	OPTEN	I	Current firmware utilizes this input pin for detecting the media density switch of the drive. Various firmware options are available for different polarities of this signal. Contact factory for available firmware options. If this pin is not driven by the drive, it should be tied low.
25	Drive Ready	nDRVRDY	I	An active low signal on this pin from the floppy disk drive, after DS0 goes active, indicates that the system may activate MTR0. If the drive does not supply this signal, this pin should be tied low.
26	Drive Power	nFDPWR	OD24	This active low signal is intended to activate an external power switch, either in the drive or on the system board, to supply power to the floppy disk drive. It is active whenever the USB97CFDC is not in SUSPEND mode.
21	RESET input	nRESET	IS	This active low signal is used by the system to reset the chip. The active low pulse should be at least 100ns wide.
22	Test output	TSTOUT	O8	This signal is used for testing the chip via an internal XNOR chain. User should normally leave it unconnected.
15	Test input	nTEST	I	This signal is a manufacturing test pin. It should be tied to VDD for normal operation.
16	Test Enable	nTESTEN	POUND AN	This active low signal places the device into board test mode using the XNOR chain. For normal operation this pin should be tied high. See Board Test Mode Operation on page 10
14 20 60	1		KOUND, AN	ID NO CONNECTS
14, 39, 60, 82, 93		VDD		+3.3V power
8, 19, 27, 43, 52, 66, 79, 81, 88		GND		Ground Reference
20, 51, 78, 80, 83, 94-96		NC		No Connect. These pins should not be connected externally.

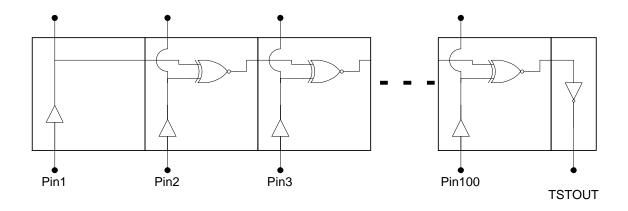
#### **BUFFER TYPE DESCRIPTIONS**

Table 1 - USB97CFDC Buffer Type Descriptions

BUFFER	DESCRIPTION
I	Input
IS	Input with Schmitt trigger
08	Output with 8mA drive
I/O8	Input/output with 8mA drive
OD12	Open drain12mA sink
024	Output with 24mA drive
OD24	Open drain24mA sink
ICLKx	XTAL clock input
OCLKx	XTAL clock output
I/O-U	See Table 6.

### **BOARD TEST MODE OPERATION**

By driving the nTESTEN pin low, the device will be placed into a special test mode to allow verification of attachment of the device to the circuit board. Every pin except the TSTOUT, XTAL2, and the power and ground pins become an input to an XNOR chain, as shown below, to allow continuity to be tested on the board. This test should individually toggle the state of the trace connected to the pin being examined for continuity, and the TSTOUT pin monitored for toggle of state. If no toggle occurs, either the pin under test is discontinuous, or the TSTOUT pin is not connected on the board



#### **DC PARAMETERS**

#### **MAXIMUM GUARANTEED RATINGS**

Operating Temperature Range0°C to +70	)°C
Storage Temperature Range55° to +150	)°C
Lead Temperature Range (soldering, 10 seconds)+325	
Positive Voltage on any pin, with respect to Ground (Note 1)	
Negative Voltage on any pin, with respect to Ground0.	
Maximum $V_{cc}$ +3.	

Note 1: Maximum voltage on all I type Inputs and the IS inputs, OD12 and OD24 outputs for floppy disk drive interface is 5.25V

\*Stresses above the specified parameters could cause permanent damage to the device. This is a stress rating only and functional operation of the device at any other condition above those indicated in the operation sections of this specification is not implied.

**Note 2:** When powering this device from laboratory or system power supplies, it is important that the Absolute Maximum Ratings not be exceeded or device failure can result. Some power supplies exhibit voltage spikes on their outputs when the AC power is switched on or off. In addition, voltage transients on the AC power line may appear on the DC output. When this possibility exists, it is suggested that a clamp circuit be used.

DC ELECTRICAL CHARACTERISTICS ( $T_A = 0^{\circ}\text{C} - 70^{\circ}\text{C}$ ,  $V_{cc} = +3.3 \text{ V} \pm 10\%$ )

PARAMETER	SYMBOL	MIN	TYP	MAX	UNITS	COMMENTS
I Type Input Buffer						
Low Input Level	V <sub>ILI</sub>			0.8	V	TTL Levels
High Input Level	V <sub>IHI</sub>	2.0			V	
ICLK Input Buffer						
Low Input Level	VILCK			0.4	V	
High Input Level	V <sub>IHCK</sub>	2.2			V	
Input Leakage (All I and IS buffers)						
Low Input Leakage	I <sub>IL</sub>	-10		+10	uA	V <sub>IN</sub> = 0
High Input Leakage	I <sub>IH</sub>	-10		+10	uA	$V_{IN} = V_{CC}$
O8 Type Buffer						
Low Output Level	V <sub>OL</sub>			0.4	V	I <sub>OL</sub> = 8 mA
High Output Level	V <sub>OH</sub>	2.4			V	I <sub>OH</sub> = -4 mA
Output Leakage	I <sub>OL</sub>	-10		+10	UA	$V_{IN} = 0$ to $V_{CC}$ (Note 1)
I/O8 Type Buffer						
Low Output Level	V <sub>OL</sub>			0.4	V	IOL = 8mA
High Output Level	V <sub>OH</sub>	2.4			V	IOH = -4mA
Output Leakage	l <sub>OL</sub>	-10		+10	μA	VIN = 0 to Vcc (Note 1)
OD12 Type Buffer						
Low Output Level	V <sub>OL</sub>			0.4	V	IOL = 12mA
Output Leakage	I <sub>OL</sub>	-10		+10	μA	VIN = 0 to Vcc (Note 1)

PARAMETER	SYMBOL	MIN	TYP	MAX	UNITS	COMMENTS
O24 Type Buffer						
Low Output Level	$V_{OL}$			0.4	V	IOL = 24mA
High Output Level	$V_{OH}$	2.4			V	IOH = -12mA
Output Leakage	I <sub>OL</sub>	-10		+10	μΑ	VIN = 0 to Vcc (Note 1)
OD24 Type Buffer						
Low Output Level	$V_{OL}$			0.4	V	IOL = 24mA
Output Leakage	l <sub>OL</sub>	-10		+10	μA	VIN = 0 to Vcc (Note 1)
IO-U						
Note 2						
Supply Current Active	I <sub>CC</sub>		30	75	MA	All outputs open.
Supply Current						
Standby	$I_{CSBU}$		120	300	μΑ	

Note 1: Output leakage is measured with the current pins in high impedance. Note 2: See Appendix A for USB DC electrical characteristics.

CAPACITANCE  $T_A = 25$ °C; fc = 1MHz;  $V_{CC} = 3.3V$ 

		LIMITS				
PARAMETER	SYMBOL	MIN	TYP	MAX	UNIT	TEST CONDITION
Clock Input Capacitance	C <sub>IN</sub>			20	pF	All pins except USB pins
Input Capacitance	C <sub>IN</sub>			10	pF	(and pins under test tied
Output Capacitance	C <sub>OUT</sub>			20	pF	to AC ground)

# **AC PARAMETERS**

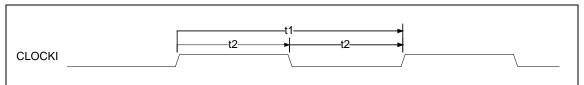


FIGURE 1 - INPUT CLOCK TIMING

Table 2 - Input Clock Timing Parameters

NAME	DESCRIPTION	MIN	TYP	MAX	UNITS
t1	Clock Cycle Time for 14.318MHz		69.84		ns
t2	Clock High Time/Low Time for 24MHz	41.9/ 27.9		27.9/ 41.9	ns
t <sub>r</sub> , t <sub>f</sub>	Clock Rise Time/Fall Time (not shown)			5	ns

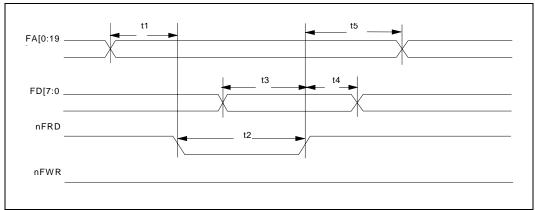


FIGURE 2 – FLASH READ TIMING

Table 3 - Flash Read Timing

NAME	PARAMETER	MIN	TYP	MAX	UNITS
t1	FA[14:0] Address setup time to nFRD asserted	40			ns
t2	nFRD pulse width	110			ns
t3	FD[7:0] Data setup time to nFRD de-asserted	30			ns
t4	FD[7:0] Data hold time from nFRD de-asserted	0			ns
t5	FA[14:0] Address hold time from nFRD de-asserted	35			ns

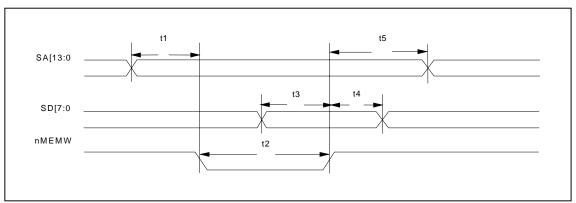


FIGURE 3 – SRAM MEMORY WRITE TIMING

**Table 4 – SRAM Memory Write Timing** 

NAME	PARAMETER	MIN	TYP	MAX	UNITS
t1	SA[19:0] valid before nMEMWR asserted	10			ns
t2	nMEMWR pulse width	100			ns
t3	SD[7:0] Data setup time to nMEMWR de-asserted	50			ns
t4	SD[7:0] Data hold time from nMEMWR de-asserted	10			ns
t5	nMEMWR de-asserted to SA[13:0] invalid	10			ns

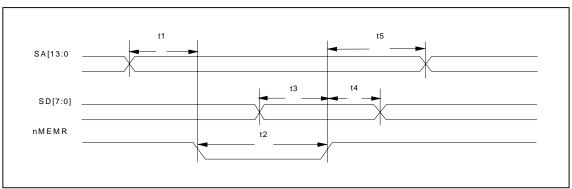
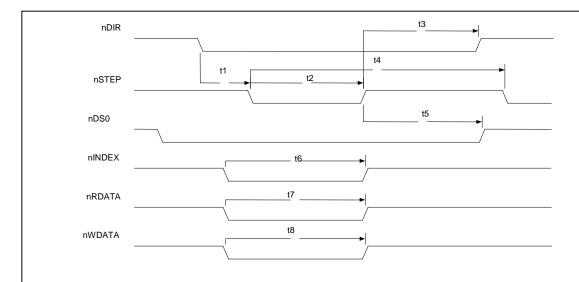


FIGURE 4 - SRAM MEMORY READ TIMING

**Table 5 – SRAM Memory Read Timing** 

	, ,					
NAME	PARAMETER	MIN	TYP	MAX	UNITS	
t1	SA[19:0] valid before nMEMRD asserted	10			ns	
t2	nMEMRD pulse width	100			ns	
t3	SD[7:0] Data setup time to nMEMRD de-asserted	50			ns	
t4	SD[7:0] Data hold time from nMEMRD de-asserted	20			ns	
t5	nMEMRD de-asserted to SA [13:0] invalid	10			ns	



NAME	PARAMETER	MIN	TYP	MAX	UNITS
t1	nDIR Set Up to nSTEP Low		4		X*
t2	nSTEP Active Time Low		24		Χ*
t3	nDIR Hold Time After nSTEP		96		X*
t4	nSTEP Cycle Time		132		Χ*
t5	nDS0-1 Hold Time from nSTEP Low		20		X*
t6	nINDEX Pulse Width		2		Χ*
t7	nRDATA Active Time Low		40		ns
t8	nWDATA Write Data Width Low		.5		Y*

<sup>\*</sup>X specifies one MCLK period and Y specifies one WCLK period.

MCLK = 16x Data Rate (at 500 Kbp/s MCLK = 8 MHz)

WCLK = 2x Data Rate (at 500 Kbp/s WCLK = 1 MHz)

FIGURE 5 - DISK DRIVE TIMING

#### **USB PARAMETERS**

The following tables and diagrams were obtained from the USB specification

### **USB DC PARAMETERS**

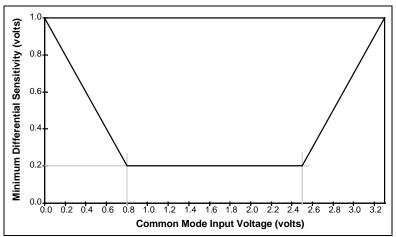


FIGURE 6 - DIFFERENTIAL INPUT SENSITIVITY OVER ENTIRE COMMON MODE RANGE

**Table 6 - DC Electrical Characteristics** 

	1 4 5 6 6	CONDITIONS	0101101100					
PARAMETER	SYMBOL	(NOTE 1, 2)	MIN	TYP	MAX	UNIT		
Supply Voltage								
Powered (Host or Hub) Port	VBUS		4.4		5.25	V		
Supply Current	1 1 2 2 2			I		-		
Function	ICC	Note 4			100	mA		
Un-configured Function (in)	ICCINIT	Note 5			100	uA		
Suspend Device	ICCS				100	uA		
Leakage Current				•				
Hi-Z State Data Line	ILO	0 V < VIN < 3.3	-10		10	uA		
Leakage		V						
Input Levels								
Differential Input Sensitivity	VDI	(D+) - (D-) , and FIGURE 6	0.2			V		
Differential Common Mode	VCM	Includes VDI	0.8		2.5	V		
Range		range						
Single Ended Receiver Threshold	VSE		8.0		2.0	V		
Output Levels	•							
Static Output Low	VOL	RL of 1.5 KΩ to 3.6 V			0.3 (3)	V		
Static Output High	VOH	RL of 15 KΩ to GND	2.8		3.6 (3)	V		
Capacitance				•				
Transceiver Capacitance	CIN	Pin to GND			20	pF		
Terminals								
Bus Pull-up Resistor on Root Port	RPU	(1.5 KΩ +/- 5%)	1.425		1.575	kΩ		
Bus Pull-down Resistor on Downstream Port	RPD	(15 KΩ +/- 5%)	14.25		15.75	kΩ		

Note 1: All voltages are measured from the local ground potential, unless otherwise specified.

Note 2: All timing use a capacitive load (CL) to ground of 50pF, unless otherwise specified.

Note 3: This is relative to VUSBIN.

**Note 4:** This is dependent on block configuration set by software.

Note 5: When the internal ring oscillator and waiting for first setup packet.

#### **USB AC PARAMETERS**

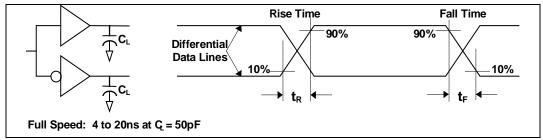


FIGURE 7 - DATA SIGNAL RISE AND FALL TIME

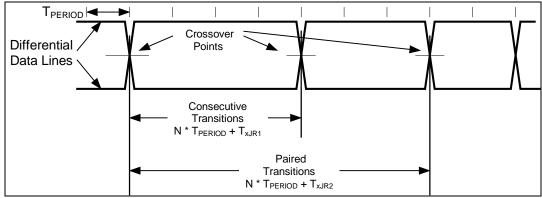


FIGURE 8 - DIFFERENTIAL DATA JITTER

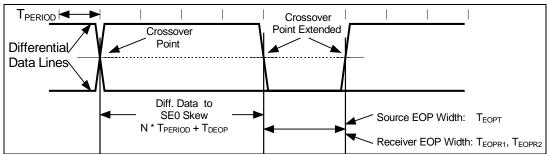


FIGURE 9 - DIFFERENTIAL TO EOP TRANSITION SKEW AND EOP WIDTH

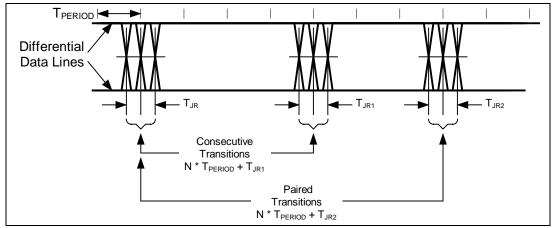


FIGURE 10 - RECEIVER JITTER TOLERANCE

Table 2 - Full Speed (12Mbps) Source Electrical Characteristics									
		CONDITIONS							
PARAMETER	SYM	(NOTE 1, 2, 3)	MIN	TYP	MAX	UNIT			
Driver Characteristics									
Transition Time:		Note 4,5 and							
D: T	-TD	FIGURE 7			00				
Rise Time	TR	CL = 50 pF	4		20	ns			
Fall Time	TF	CL = 50 pF	4		20	ns			
Rise/Fall Time Matching	TRFM	(TR/TF)	90		110	%			
Output Signal	VCRS		1.3		2.0	V			
Crossover Voltage									
Drive Output	ZDRV	Steady State Drive	28		43	$\Omega$			
Resistance									
Data Source Timing									
Full Speed Data Rate	TDRATE	Ave. Bit Rate	11.95		12.03	Mbs			
		(12 Mb/s +/-							
		0.25%) Note 8							
Frame Interval	TFRAME	1.0 ms +/- 0.05%	0.999		1.0005	ms			
5			5						
Source Differential		Note 6, 7 and							
Driver Jitter	TDJ1	FIGURE 8	-3.5		3.5	20			
To next Transition	TDJ1		-3.5 -4.0		4.0	ns ns			
For Paired Transitions	1002		-4.0		4.0	113			
Source EOP Width	TEOPT	Note 7 and	160		175	ns			
Journal Width	12011	FIGURE 9	100		173	113			
Differential to EOP	TDEOP	Note 7 and	-2		5	ns			
transition Skew		FIGURE 9							
Receiver Data Jitter		Note 7 and							
Tolerance		FIGURE 10							
To next Transition	TJR1		-18.5		18.5	ns			
For Paired Transitions	TJR2		-9		9.0	ns			
EOP Width at receiver		Note 7 and							
Most seis et es EOD		FIGURE 9							
Must Assert	TEOPR1		40			na			
Must Accept	TEOPR1		40 82			ns ns			
Cable Impedance and Timing									
Cable Impedance (Full	ZO	(45 Ω +/- 15%)	38.75		51.75	0			
Speed)	20	(45 12 +/+ 15%)	30.73		31.73	Ω			
Cable Delay (One Way)	TCBL				30	ns			

- Note 1: All voltages are measured from the local ground potential, unless otherwise specified.
- Note 2: All timing use a capacitive load (CL) to ground of 50pF, unless otherwise specified.
- **Note 3:** Full speed timings have a  $1.5K\Omega$  pull-up to 2.8 V on the D+ data line.
- Note 4: Measured from 10% to 90% of the data signals.
- **Note 5:** The rising and falling edges should be smoothly transiting (monotonic).
- Note 6: Timing differences between the differential data signals.
- **Note 7:** Measured at crossover point of differential data signals.
- Note 8: These are relative to the 14.318 MHz crystal.

# **MECHANICAL OUTLINE**

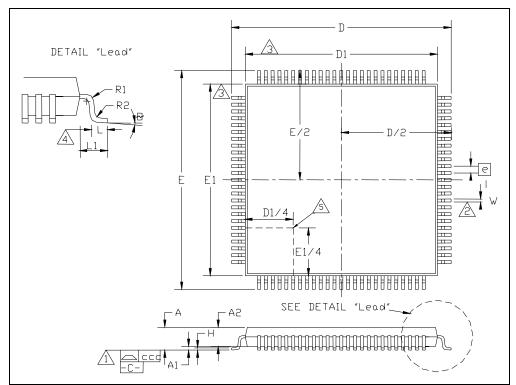


FIGURE 11 - 100 PIN TQFP PACKAGE

	MIN	NOMINAL	MAX	REMARK	
Α	~	~	1.60	Overall Package Height	
A1	0.05	~	0.15	Standoff	
A2	1.35	1.40	1.45	Body Thickness	
D	13.80	14.00	14.20	X Span	
D/2	6.90	7.00	7.10	<sup>1</sup> / <sub>2</sub> X Span Measure from Centerline	
D1	11.80	12.00	12.20	X body Size	
Е	13.80	14.00	14.20	Y Span	
E/2	6.90	7.00	7.10	<sup>1</sup> / <sub>2</sub> Y Span Measure from Centerline	
E1	11.80	12.00	12.20	Y body Size	
Н	0.09	~	0.20	Lead Frame Thickness	
L	0.45	0.60	0.75	Lead Foot Length from Centerline	
L1	~	1.00	~	Lead Length	
е		0.40 Basic		Lead Pitch	
	0°	3.5°	7°	Lead Foot Angle	
W	0.13	0.16	0.23	Lead Width	
R1	0.08	~	~	Lead Shoulder Radius	
R2	0.08	~	0.20	Lead Foot Radius	
CCC	~	~	0.08	Coplanarity	

Note 1: Controlling Unit: millimeter

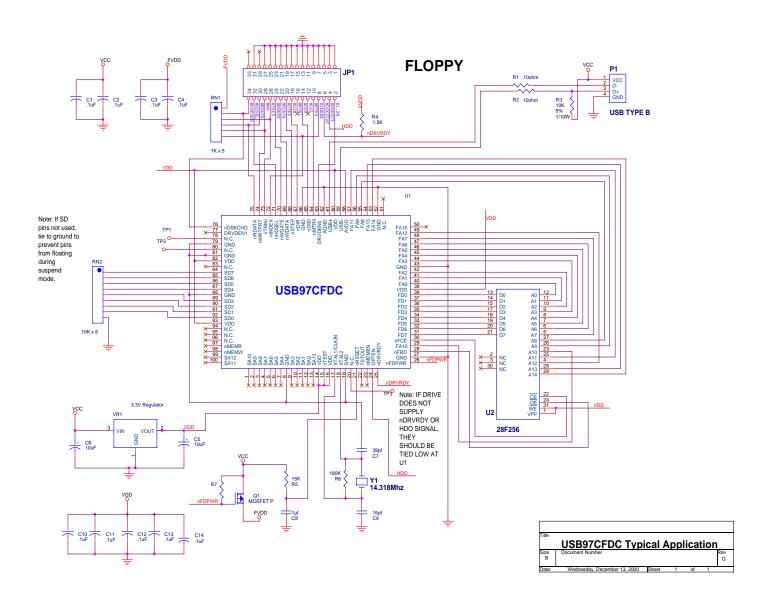
Note 2: Minimum space between protrusion and an adjacent lead is .007 mm.

Note 3: Package body dimensions D1 and E1 do not include the mold protrusion. Maximum mold protrusion is 0.25 mm

Note 5: Details of pin 1 identifier are optional but must be located within the zone indicated.

### **APPENDIX A:**

### **USB97CFDC TYPICAL APPLICATION**



#### SMSC PROVIDED SOFTWARE FOR USB97CFDC

SMSC provides the following for the USB97CFDC:

- I. Program firmware with the following features:
  - (a) Supports 640K, 720K, 1.44M, 1.2M Windows J, 1.2M NEC DOS 6.x formats.
  - (b) Supports USB Mass Storage Class compliant drivers from Apple and Microsoft as well as SMSC's Windows 98 driver.
  - (c) Supports USB Mass Storage compliant bootable floppy BIOS.
  - (d) 4ms Seek times.
  - (e) USB 1.1 compliance, including low power device class SUSPEND mode operation and power control of disk drive.
  - (f) Disk drive feedback of readiness upon power re-application (optional).
  - (g) Option for using drive media density sense output (HDO#) pin to prevent attempts to format 2DD disks as 2HD.
- II. USB Mass Storage Class compliant driver for Windows 98.

# **USB97CFDC REVISIONS**

PAGE(S)	SECTION/FIGURE/ENTRY	CORRECTION	DATE REVISED
19	USB97CFDC TYPICAL APPLICATION	Updated schematic	12/15/00
19	USB97CFDC TYPICAL APPLICATION	Updated schematic	11/01/00